DOCUMENT CHANGE REQUEST

DCR number 685
Changes required for: N/A
Originator: Benoit Cornanguer
Date: 2011/12/06
Date sent: 2011/10/26
Organisation: STMicroelectronics
Status: IMPLEMENTED

Title:	TRANSISTORS, POWER, MOSFET, N-CHANNEL, RAD-HARD BASED ON TYPE STRH100N6		
Number:	5205/022	Issue:	1

Other documents affected:

Page:

pages 10 & 11

Paragraph:

Paragraph 2.5.1 Room Temperature Electrical Measurements

Original wording:

The limits of the AC test parameters [Qgs-Qgd-td(on)-tr-td(off)-tf] need to be updated as defined below:
Qgs: maximum limit=43nC instead of 33nC
Qgd: minimum limit=34nC instead of 39nC
td(on): maximum limit=34ns instead of 33.5ns
tr: maximum limit=140ns instead of 135ns
td(off): maximum limit=110ns instead of 93ns
tf: minimum limit=45ns instead of 62ns

Proposed wording:

Justification:

The ESCC detail specification has been written from the characterization results.
All AC electrical test parameters during the characterization phase have been done near of the body of the TO-254AA package.
Unlike for the ESCC qualification we have used a test socket; in this case we lost performance for the switching times and gate charge due to that the measurements are done more far of the body of the package.
If we take into account this statement, we are sure to cover all customer applications by giving to them the worst limits.
(This is not the case if we keep the limits defined after the characterization).

Attachments:
N/A
Modifications:
N/A
Approval signature:
Date signed:
2011-12-06